

## Automotive-grade N-channel 40 V, 1.5 mΩ typ., 180 A STripFET™ F7 Power MOSFET in a TO-220 package

Datasheet - production data

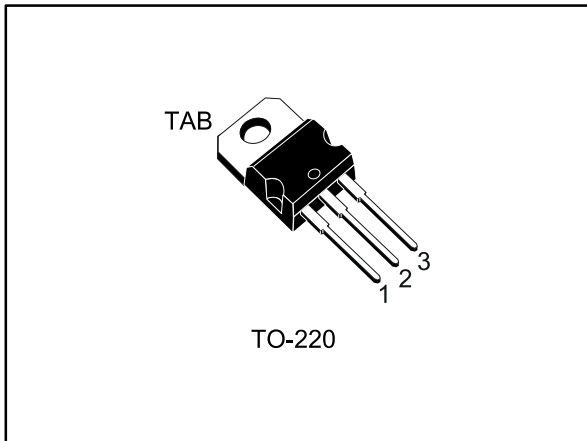
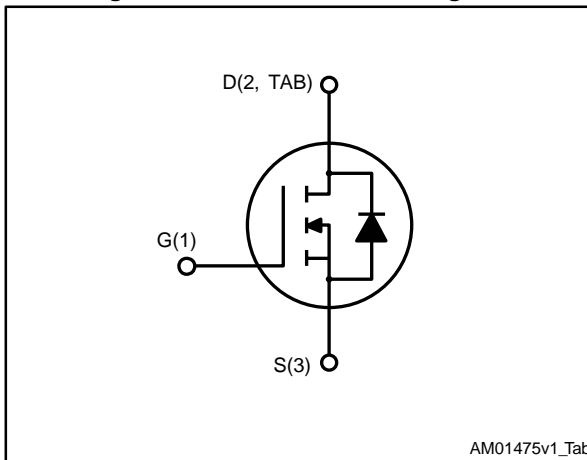


Figure 1: Internal schematic diagram



### Features

| Order code   | V <sub>DS</sub> | R <sub>DS(on)</sub> max. | I <sub>D</sub> | P <sub>TOT</sub> |
|--------------|-----------------|--------------------------|----------------|------------------|
| STP410N4F7AG | 40 V            | 1.8 mΩ                   | 180 A          | 365 W            |

- Designed for automotive applications and AEC-Q101 qualified
- Among the lowest R<sub>DS(on)</sub> on the market
- Excellent FoM (figure of merit)
- Low C<sub>rss</sub>/C<sub>iss</sub> ratio for EMI immunity
- High avalanche ruggedness

### Applications

- Switching applications

### Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

| Order code   | Marking | Package | Packing |
|--------------|---------|---------|---------|
| STP410N4F7AG | 410N4F7 | TO-220  | Tube    |

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# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

| Symbol         | Parameter  | Value      | Unit |
|----------------|--|------------|------|
| $V_{DS}$       | Drain-source voltage                                     | 40         | V    |
| $V_{GS}$       | Gate-source voltage                                      | $\pm 20$   | V    |
| $I_D^{(1)}$    | Drain current (continuous) at $T_{case} = 25\text{ °C}$  | 180        | A    |
|                | Drain current (continuous) at $T_{case} = 100\text{ °C}$ | 180        |      |
| $I_{DM}^{(2)}$ | Drain current (pulsed)                                   | 720        | A    |
| $P_{TOT}$      | Total dissipation at $T_{case} = 25\text{ °C}$           | 365        | W    |
| $E_{AS}^{(3)}$ | Single pulse avalanche energy                            | 1.9        | J    |
| $T_{stg}$      | Storage temperature range                                | -55 to 175 | °C   |
| $T_j$          | Operating junction temperature range                     |            |      |

**Notes:**

(1) Current is limited by package, the current capability of the silicon is 350 A at 25 °C.

(2) Pulse width is limited by safe operating area.

(3)  $T_j \leq 175\text{ °C}$ ,  $I_{av}=80\text{A}$

**Table 3: Thermal data**

| Symbol         | Parameter                               | Value | Unit |
|----------------|---|-------|------|
| $R_{thj-case}$ | Thermal resistance junction-case        | 0.41  | °C/W |
| $R_{thj-amb}$  | Thermal resistance junction-ambient max | 62.5  |      |

## 2 Electrical characteristics

( $T_{\text{case}} = 25\text{ °C}$  unless otherwise specified)

**Table 4: Static**

| Symbol                      | Parameter                         | Test conditions   | Min. | Typ. | Max. | Unit          |
|-----------------------------|-----------------------------------|---|------|------|------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage    | $V_{\text{GS}} = 0\text{ V}$ , $I_{\text{D}} = 250\text{ }\mu\text{A}$                                    | 40   |      |      | V             |
| $I_{\text{DSS}}$            | Zero gate voltage drain current   | $V_{\text{GS}} = 0\text{ V}$ , $V_{\text{DS}} = 40\text{ V}$  |      |      | 10   | $\mu\text{A}$ |
|                             |                                   | $V_{\text{GS}} = 0\text{ V}$ , $V_{\text{DS}} = 40\text{ V}$ ,<br>$T_{\text{case}} = 125\text{ °C}^{(1)}$ |      |      | 100  |               |
| $I_{\text{GSS}}$            | Gate-body leakage current         | $V_{\text{DS}} = 0\text{ V}$ , $V_{\text{GS}} = 20\text{ V}$  |      |      | 200  | nA            |
| $V_{\text{GS(th)}}$         | Gate threshold voltage            | $V_{\text{DS}} = V_{\text{GS}}$ , $I_{\text{D}} = 250\text{ }\mu\text{A}$                                 | 2.5  |      | 4.5  | V             |
| $R_{\text{DS(on)}}$         | Static drain-source on-resistance | $V_{\text{GS}} = 10\text{ V}$ , $I_{\text{D}} = 90\text{ A}$  |      | 1.5  | 1.8  | m $\Omega$    |

**Notes:**

<sup>(1)</sup>Defined by design, not subject to production test.

**Table 5: Dynamic**

| Symbol           | Parameter                    | Test conditions  | Min. | Typ.  | Max. | Unit        |
|------------------|------------------------------|--|------|-------|------|-------------|
| $C_{\text{iss}}$ | Input capacitance            | $V_{\text{DS}} = 25\text{ V}$ , $f = 1\text{ MHz}$ , $V_{\text{GS}} = 0\text{ V}$  | -    | 11700 | -    | $\text{pF}$ |
| $C_{\text{oss}}$ | Output capacitance           |  | -    | 3500  | -    |             |
| $C_{\text{rss}}$ | Reverse transfer capacitance |  | -    | 390   | -    |             |
| $Q_{\text{g}}$   | Total gate charge            | $V_{\text{DD}} = 20\text{ V}$ , $I_{\text{D}} = 180\text{ A}$ , $V_{\text{GS}} = 10\text{ V}$<br>(see <a href="#">Figure 14: "Test circuit for gate charge behavior"</a> ) | -    | 140   | -    | nC          |
| $Q_{\text{gs}}$  | Gate-source charge           |  | -    | 65    | -    |             |
| $Q_{\text{gd}}$  | Gate-drain charge            |  | -    | 27    | -    |             |

**Table 6: Switching times**

| Symbol              | Parameter           | Test conditions  | Min. | Typ. | Max. | Unit |
|---------------------|---------------------|--|------|------|------|------|
| $t_{\text{d(on)}}$  | Turn-on delay time  | $V_{\text{DD}} = 20\text{ V}$ , $I_{\text{D}} = 90\text{ A}$ $R_{\text{G}} = 4.7\text{ }\Omega$ ,<br>$V_{\text{GS}} = 10\text{ V}$ (see <a href="#">Figure 13: "Test circuit for resistive load switching times"</a> and ) | -    | 35   | -    | ns   |
| $t_{\text{r}}$      | Rise time           |  | -    | 200  | -    |      |
| $t_{\text{d(off)}}$ | Turn-off delay time |  | -    | 110  | -    |      |
| $t_{\text{f}}$      | Fall time           |  | -    | 44   | -    |      |

Table 7: Source-drain diode

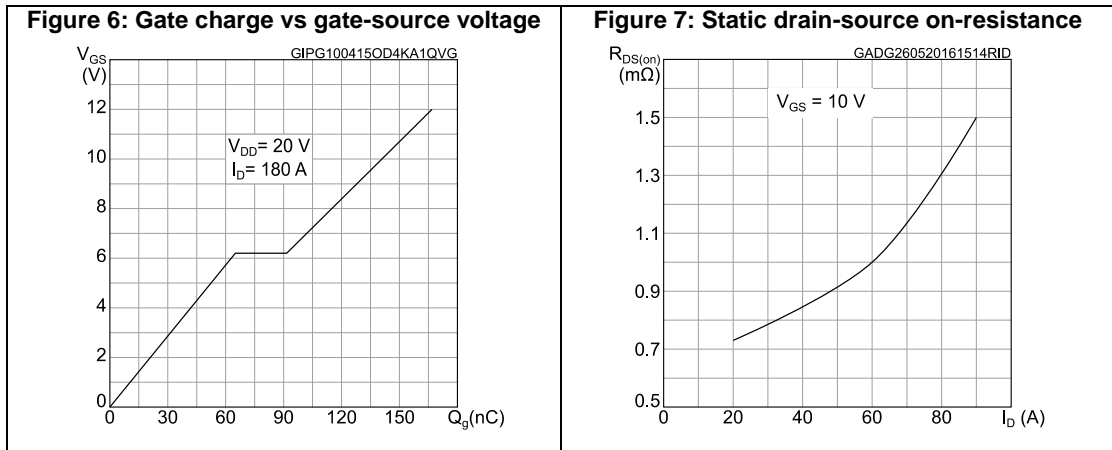
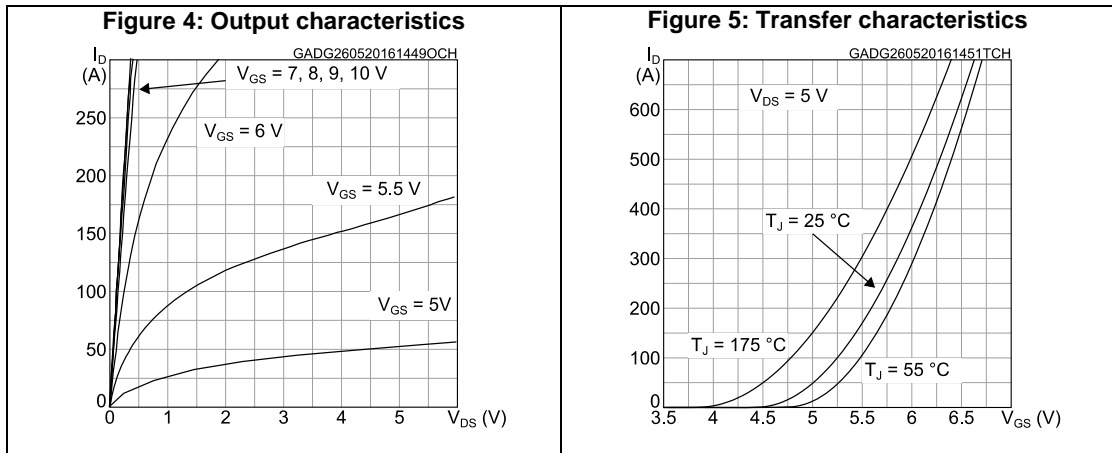
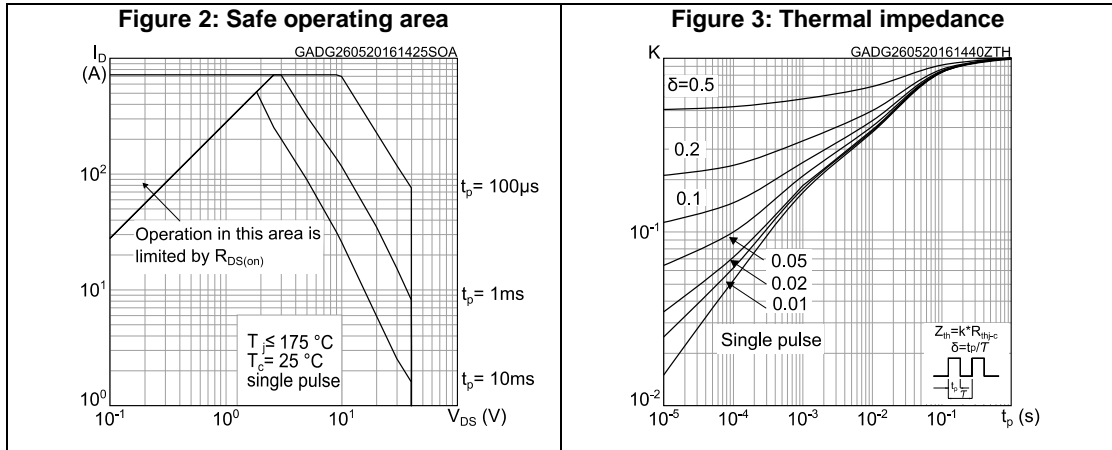
| Symbol         | Parameter                | Test conditions  | Min. | Typ. | Max. | Unit |
|----------------|--------------------------|--|------|------|------|------|
| $I_{SD}^{(1)}$ | Source-drain current     |  | -    |      | 180  | A    |
| $V_{SD}^{(2)}$ | Forward on voltage       | $V_{GS} = 0\text{ V}$ , $I_{SD} = 90\text{ A}$   | -    |      | 1.3  | V    |
| $t_{rr}$       | Reverse recovery time    | $I_{SD} = 180\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 32\text{ V}$ , $T_j = 25\text{ }^\circ\text{C}$ (see <a href="#">Figure 15: "Test circuit for inductive load switching and diode recovery times"</a> ) | -    | 74.4 |      | ns   |
| $Q_{rr}$       | Reverse recovery charge  |  | -    | 115  |      | nC   |
| $I_{RRM}$      | Reverse recovery current |  | -    | 3.1  |      | A    |

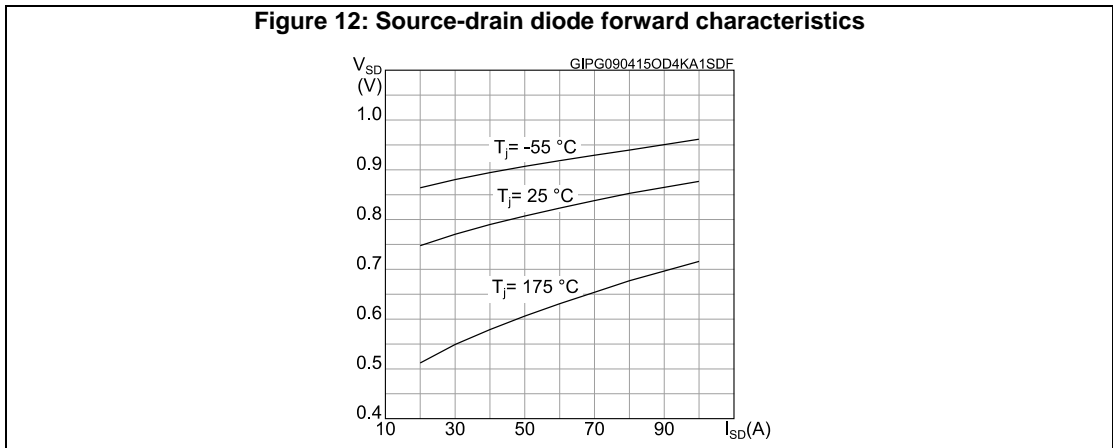
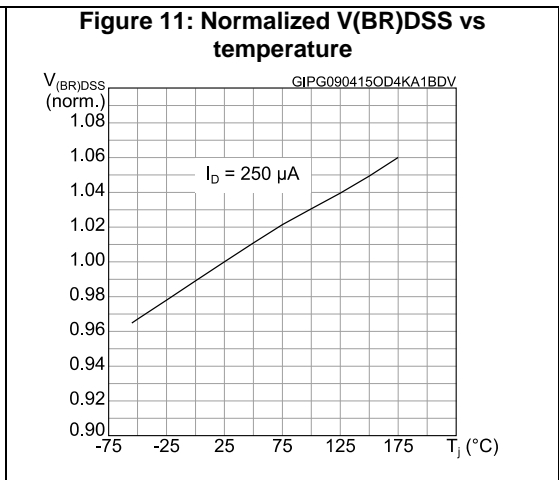
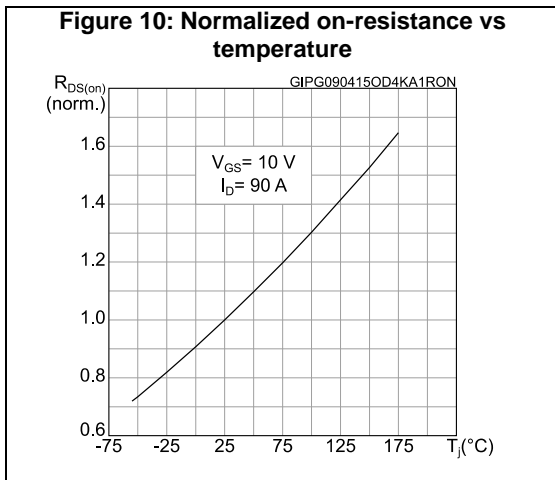
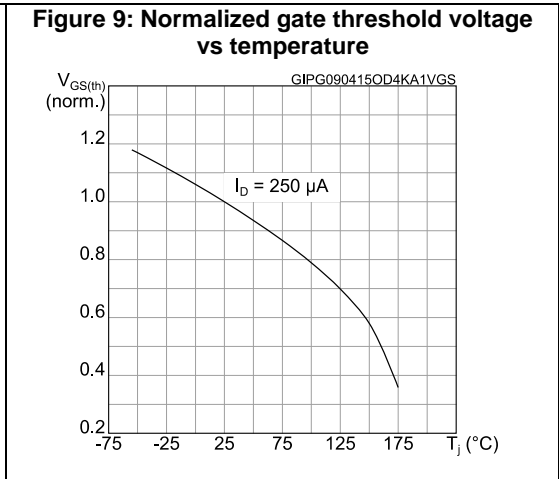
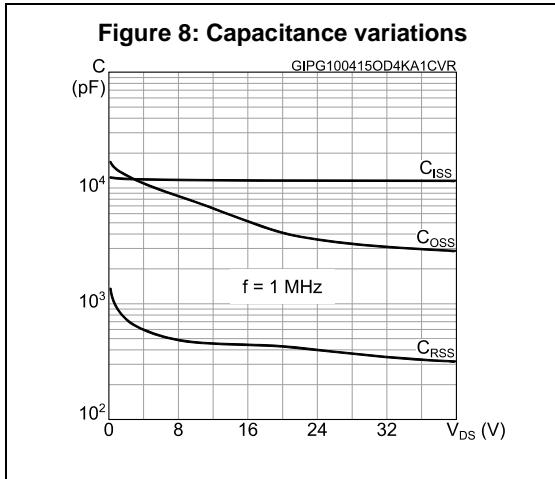
**Notes:**

(1) Current is limited by package, the current capability of the silicon is 350 A at 25 °C.

(2) Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)





### 3 Test circuits

**Figure 13: Test circuit for resistive load switching times**



AM01468v1

**Figure 14: Test circuit for gate charge behavior**



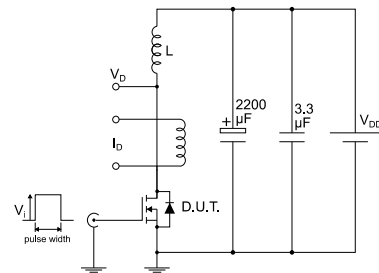
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**Figure 15: Test circuit for inductive load switching and diode recovery times**



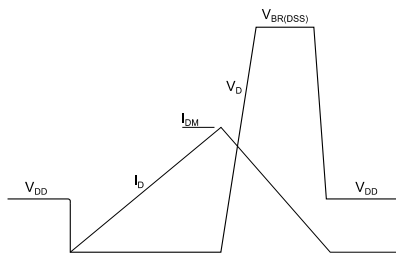
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**Figure 16: Unclamped inductive load test circuit**



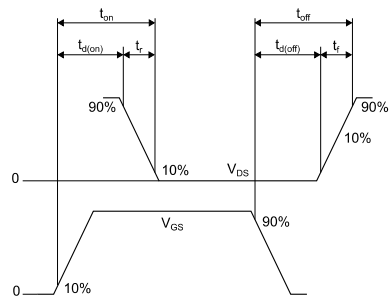
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**Figure 17: Unclamped inductive waveform**



AM01472v1

**Figure 18: Switching time waveform**



AM01473v1



## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

### 4.1 TO-220 package information

Figure 19: TO-220 type A package outline

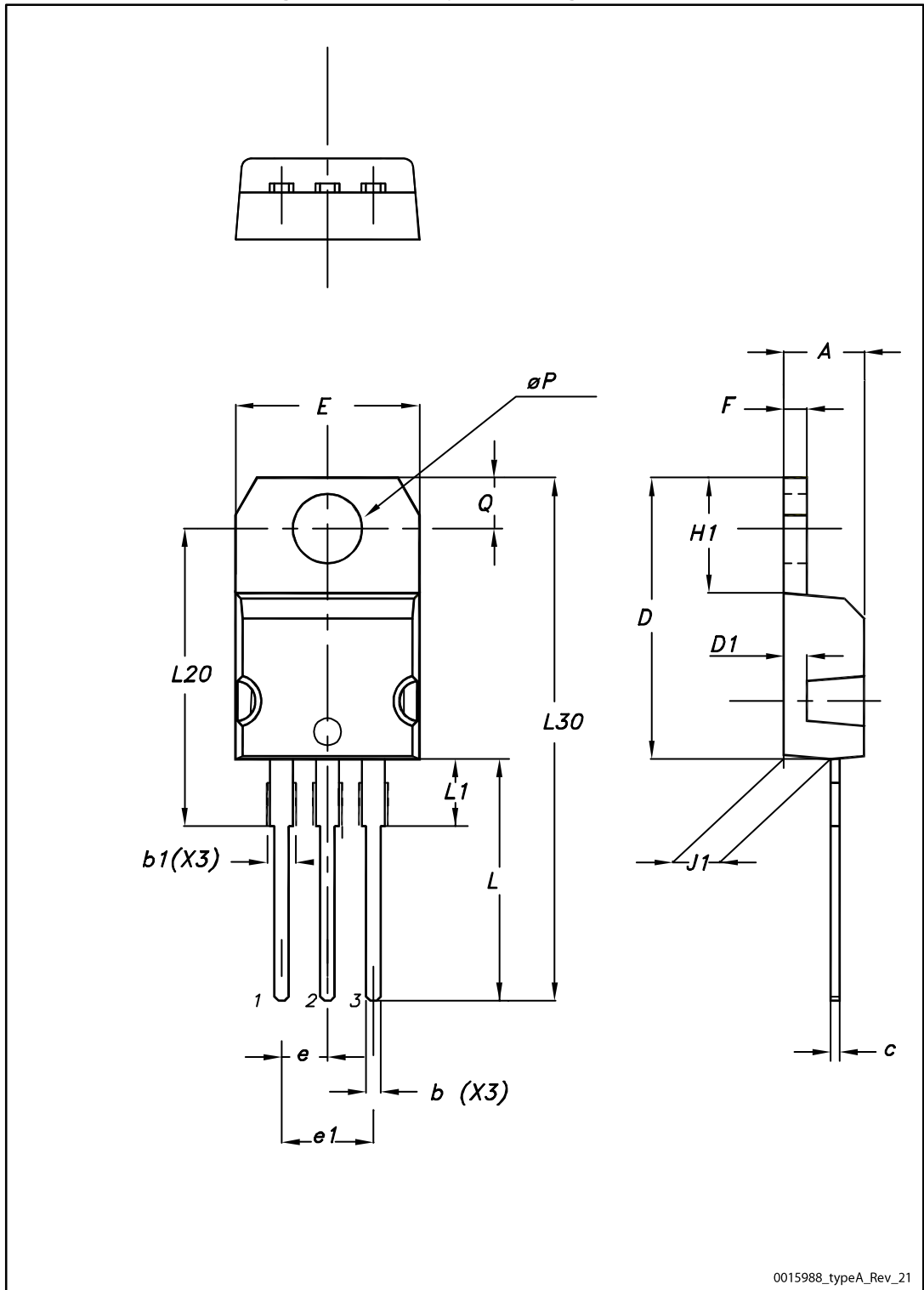


Table 8: TO-220 type A mechanical data

| Dim. | mm    |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.40  |       | 4.60  |
| b    | 0.61  |       | 0.88  |
| b1   | 1.14  |       | 1.55  |
| c    | 0.48  |       | 0.70  |
| D    | 15.25 |       | 15.75 |
| D1   |       | 1.27  |       |
| E    | 10.00 |       | 10.40 |
| e    | 2.40  |       | 2.70  |
| e1   | 4.95  |       | 5.15  |
| F    | 1.23  |       | 1.32  |
| H1   | 6.20  |       | 6.60  |
| J1   | 2.40  |       | 2.72  |
| L    | 13.00 |       | 14.00 |
| L1   | 3.50  |       | 3.93  |
| L20  |       | 16.40 |       |
| L30  |       | 28.90 |       |
| øP   | 3.75  |       | 3.85  |
| Q    | 2.65  |       | 2.95  |

## 5 Revision history

Table 9: Document revision history

| Date        | Revision | Changes        |
|-------------|----------|----------------|
| 25-May-2016 | 1        | First release. |

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